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L1	1	("6528219").PN.	USPAT	OR	OFF	2005/07/21 18:21
L2	499	wafer adj3 error	USPAT	OR	OFF	2005/07/21 18:22
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L5	6987	(mean adj3 error)	USPAT	OR	OFF	2005/07/21 18:22
L6	4	5 and 2	USPAT	OR	OFF	2005/07/21 18:24
L7	1243	(430/30).CCLS.	USPAT	OR	OFF	2005/07/21 18:25
L8	729	7 and wafer	USPAT	OR	OFF	2005/07/21 18:25
L9	348	8 and error	USPAT	OR	OFF	2005/07/21 18:25
L10	49	9 and residual	USPAT	OR	OFF	2005/07/21 19:12
L11	0	(over adj3 lay adj3 sites)	USPAT	OR	OFF	2005/07/21 18:50
L12	0	(over adj3 lay adj3 sites)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/21 18:51
L13	39	(overlay adj3 sites)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/21 18:51
L14	36	13 and field	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/07/21 18:51
L15	149	(Field adj3 image adj3 alignment)	USPAT	OR	OFF	2005/07/21 19:12
L16	154	(Field adj3 image adj3 alignment)	USPAT	OR	ON	2005/07/21 19:12
L17	0	16 and (field-to-field)	USPAT	OR	ON	2005/07/21 19:13
L18	154	16 and (field samefield)	USPAT	OR	ON	2005/07/21 19:13
L19	154	16 and (field same field)	USPAT	OR	ON	2005/07/21 19:13
L20	0	16 and (field adj to adj field)	USPAT	OR	ON	2005/07/21 19:13
L21	17	16 and (residual adj3 error)	USPAT	OR	ON	2005/07/21 19:23
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## » Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

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 Geoscience and Remote Sensing, IEEE Transactions on  
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 Engineering in Medicine and Biology Society, 1998. Proceedings of the 20th Annual International Conference of the IEEE  
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 Zhong, J.; Adrian, R.J.; Huang, T.S.;  
 Acoustics, Speech, and Signal Processing, 1993. ICASSP-93., 1993 IEEE International Conference on  
 Volume 5, 27-30 April 1993 Page(s):181 - 184 vol.5  
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 Kastella, K.;  
 Automatic Control, IEEE Transactions on  
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 Digital Object Identifier 10.1109/9.388686  
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- 5. Current dipole localization with an ideal magnetometer system  
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 Biomedical Engineering, IEEE Transactions on  
 Volume 43, Issue 11, Nov. 1996 Page(s):1049 - 1061  
 Digital Object Identifier 10.1109/10.541247  
[AbstractPlus](#) | [References](#) | Full Text: [PDF\(1184 KB\)](#) [IEEE JNL](#)
  
- 6. Classifier fusion results using various open literature data sets  
 Lynch, R.S., Jr.; Willett, P.K.;  
 Systems, Man and Cybernetics, 2003. IEEE International Conference on  
 Volume 1, 5-8 Oct. 2003 Page(s):723 - 728 vol.1  
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Microwave Theory and Techniques, IEEE Transactions on  
Volume 49, Issue 12, Dec. 2001 Page(s):2573 - 2579  
Digital Object Identifier 10.1109/22.971652

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